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#### What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "<u>Embedded -</u> <u>Microcontrollers</u>"

### Details

Product Status	Obsolete
Core Processor	RL78
Core Size	16-Bit
Speed	24MHz
Connectivity	CSI, I <sup>2</sup> C, UART/USART
Peripherals	DMA, LVD, POR, PWM, WDT
Number of I/O	14
Program Memory Size	2KB (2K x 8)
Program Memory Type	FLASH
EEPROM Size	2K x 8
RAM Size	256 x 8
Voltage - Supply (Vcc/Vdd)	1.8V ~ 5.5V
Data Converters	A/D 11x8/10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	20-LSSOP (0.173", 4.40mm Width)
Supplier Device Package	20-LSSOP
Purchase URL	https://www.e-xfl.com/product-detail/renesas-electronics-america/r5f10266asp-v5

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

Code flash	Data flash	RAM	20 pins	24 pins	30 pins
16 KB	2 KB	2 KB	_	_	R5F102AA
	_		_	_	R5F103AA
	2 KB	1.5 KB	R5F1026A Note 1	R5F1027A <sup>Note 1</sup>	_
			R5F1036A Note 1	R5F1037A Note 1	_
12 KB	2KB	1 KB	R5F10269 Note 1	R5F10279 Note 1	R5F102A9
			R5F10369 Note 1	R5F10379 Note 1	R5F103A9
8 KB	2 KB	768 B	R5F10268 Note 1	R5F10278 Note 1	R5F102A8
			R5F10368 Note 1	R5F10378 Note 1	R5F103A8
4 KB	2KB	512 B	R5F10267	R5F10277	R5F102A7
	_		R5F10367	R5F10377	R5F103A7
2 KB	2 KB	256 B	R5F10266 Note 2		_
			R5F10366 Note 2		

O ROM, RAM capacities

Notes 1. This is 640 bytes when the self-programming function or data flash function is used. (For details, see CHAPTER 3 CPU ARCHITECTURE.)

2. The self-programming function cannot be used for R5F10266 and R5F10366.

**Caution** When the flash memory is rewritten via a user program, the code flash area and RAM area are used because each library is used. When using the library, refer to RL78 Family Flash Self Programming Library Type01 User's Manual and RL78 Family Data Flash Library Type04 User's Manual.



<R>

## 1.2 List of Part Numbers



### Figure 1-1. Part Number, Memory Size, and Package of RL78/G12

Notes 1. For details about the differences between the R5F102 products and the R5F103 products of RL78/G12, see 1.1 Differences between the R5F102 Products and the R5F103 Products.

2. Products only for "A: Consumer applications ( $T_A = -40$  to  $+85^{\circ}C$ )" and "D: Industrial applications ( $T_A = -40$  to  $+85^{\circ}C$ )"



## 1.3 Differences between the R5F102 Products and the R5F103 Products

The following are differences between the R5F102 products and the R5F103 products.

- O Whether the data flash memory is mounted or not
- O High-speed on-chip oscillator oscillation frequency accuracy
- O Number of channels in serial interface
- O Whether the DMA function is mounted or not
- O Whether a part of the safety functions are mounted or not

### 1.3.1 Data Flash

The data flash memory of 2 KB is mounted on the R5F102 products, but not on the R5F103 products.

Product	Data Flash
R5F102 products	2KB
R5F1026A, R5F1027A, R5F102AA,	
R5F10269, R5F10279, R5F102A9,	
R5F10268, R5F10278, R5F102A8,	
R5F10267, R5F10277, R5F102A7,	
R5F10266 Note	
R5F103 products	Not mounted
R5F1036A, R5F1037A, R5F103AA,	
R5F10369, R5F10379, R5F103A9,	
R5F10368, R5F10378 R5F103A8,	
R5F10367, R5F10377, R5F103A7,	
R5F10366	

- **Note** The RAM in the R5F10266 has capacity as small as 256 bytes. Depending on the customer's program specification, the stack area to execute the data flash library may not be kept and data may not be written to or erased from the data flash memory.
- **Caution** When the flash memory is rewritten via a user program, the code flash area and RAM area are used because each library is used. When using the library, refer to RL78 Family Flash Self Programming Library Type01 User's Manual and RL78 Family Data Flash Library Type04 User's Manual.



### $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, \text{V}_{SS} = 0 \text{ V})$

(3/4)

					1		(0, 1)
Parameter	Symbol	Condition	Conditions			MAX.	Unit
Input voltage, high	VIH1	Normal input buffer 20-, 24-pin products: P00 to P0 P40 to P42	03 <sup>№0te 2</sup> , P10 to P14,	0.8Vdd		Vdd	V
		30-pin products: P00, P01, P1 P40, P50, P51, P120, P147	0 to P17, P30, P31,				
	VIH2	TTL input buffer	$4.0~V \leq V_{\text{DD}} \leq 5.5~V$	2.2		VDD	V
		20-, 24-pin products: P10, P11	$3.3~V \leq V_{\text{DD}} < 4.0~V$	2.0		VDD	V
		30-pin products: P01, P10, P11, P13 to P17	$1.8~V \leq V_{\text{DD}} < 3.3~V$	1.5		Vdd	V
	Vінз	P20 to P23		0.7Vdd		VDD	v
	VIH4	P60, P61		0.7Vdd		6.0	V
	VIH5	P121, P122, P125 <sup>Note 1</sup> , P137, I	EXCLK, RESET	0.8Vdd		VDD	V
Input voltage, low	VIL1	Normal input buffer		0		0.2VDD	V
		20-, 24-pin products: P00 to P03 <sup>Note 2</sup> , P10 to P14, P40 to P42					
		30-pin products: P00, P01, P10 P40, P50, P51, P120, P147	) to P17, P30, P31,				
	VIL2	TTL input buffer	$4.0~V \leq V_{\text{DD}} \leq 5.5~V$	0		0.8	V
		20-, 24-pin products: P10, P11	$3.3~V \leq V_{\text{DD}} < 4.0~V$	0		0.5	V
		30-pin products: P01, P10, P11, P13 to P17	$1.8~V \leq V_{\text{DD}} < 3.3~V$	0		0.32	V
	VIL3	P20 to P23		0		0.3Vdd	V
	VIL4	P60, P61		0		0.3Vdd	V
	VIL5	P121, P122, P125 <sup>Note 1</sup> , P137, I	EXCLK, RESET	0		0.2VDD	V
Output voltage, high	Vон1	20-, 24-pin products: P00 to P03 <sup>№te 2</sup> , P10 to P14,	$\begin{array}{l} 4.0 \ V \leq V_{\text{DD}} \leq 5.5 \ V, \\ I_{\text{OH1}} = -10.0 \ mA \end{array} \end{array} \label{eq:VDD}$	Vdd-1.5			V
		P40 to P42 30-pin products:	4.0 V $\leq$ V <sub>DD</sub> $\leq$ 5.5 V, I <sub>OH1</sub> = -3.0 mA	VDD-0.7			V
	P00, P01, P10 to P17, P30, P31, P40, P50, P51, P120, P147	P00, P01, P10 to P17, P30, P31, P40, P50, P51, P120,	$\begin{array}{l} 2.7 \ V \leq V_{\text{DD}} \leq 5.5 \ V, \\ I_{\text{OH1}} = -2.0 \ mA \end{array} \end{array} \label{eq:VDD}$	VDD-0.6			V
		$\begin{array}{l} 1.8 \ V \leq V_{\text{DD}} \leq 5.5 \ V, \\ I_{\text{OH1}} = -1.5 \ mA \end{array}$	VDD-0.5			V	
	V <sub>OH2</sub>	P20 to P23	Iон₂ = −100 <i>µ</i> А	VDD-0.5			V

**Notes 1.** 20, 24-pin products only.

2. 24-pin products only.

- Caution The maximum value of V<sub>IH</sub> of pins P10 to P12 and P41 for 20-pin products, P01, P10 to P12, and P41 for 24pin products, and P00, P10 to P15, P17, and P50 for 30-pin products is V<sub>DD</sub> even in N-ch open-drain mode. High level is not output in the N-ch open-drain mode.
- **Remark** Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.



### Minimum Instruction Execution Time during Main System Clock Operation



When the high-speed on-chip oscillator clock is selected During self programming When high-speed system clock is selected \_ \_ \_

\_ . \_ .



TCY vs VDD (LS (low-speed main) mode)

When the high-speed on-chip oscillator clock is selected

--- During self programming ---. When high-speed system clock is selected





### CSI mode connection diagram (during communication at same potential)





CSI mode serial transfer timing (during communication at same potential) (When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.)



(Remarks are listed on the next page.)



- 5. This value as an example is calculated when the conditions described in the "Conditions" column are met. Refer to Note 4 above to calculate the maximum transfer rate under conditions of the customer.
- 6. The smaller maximum transfer rate derived by using fMCK/6 or the following expression is the valid maximum transfer rate.

Expression for calculating the transfer rate when 2.7 V  $\leq$  V\_DD < 4.0 V and 2.3 V  $\leq$  V\_b  $\leq$  2.7 V

Maximum transfer rate = 
$$\frac{1}{\{-Cb \times Rb \times ln (1 - \frac{2.0}{Vb})\} \times 3}$$
 [bps]

Baud rate error (theoretical value) =

 $\begin{array}{c} \displaystyle \frac{1}{\text{Transfer rate} \times 2} - \{-C_b \times R_b \times \ln (1 - \frac{2.0}{V_b})\} \\ \hline \\ \displaystyle (\frac{1}{\text{Transfer rate}}) \times \text{Number of transferred bits} \end{array} \times 100 \ [\%]$ \* This value is the theoretical value of the relative difference between the transmission and reception sides.

- 7. This value as an example is calculated when the conditions described in the "Conditions" column are met. Refer to Note 6 above to calculate the maximum transfer rate under conditions of the customer.
- 8. The smaller maximum transfer rate derived by using fMCK/6 or the following expression is the valid maximum transfer rate.

Expression for calculating the transfer rate when 1.8 V  $\leq$  V\_DD < 3.3 V, 1.6 V  $\leq$  V\_b  $\leq$  2.0 V

Maximum transfer rate = 
$$\frac{1}{\{-C_b \times R_b \times \ln (1 - \frac{1.5}{V_b})\} \times 3}$$
 [bps]

Baud rate error (theoretical value) =

$$\frac{1}{\text{ransfer rate} \times 2} - \{-C_b \times R_b \times \ln (1 - \frac{1.5}{V_b})\}$$

$$\frac{1}{(1 - \frac{1.5}{V_b})} \times 100 \,[\%]$$
Transfer rate

\* This value is the theoretical value of the relative difference between the transmission and reception sides.

- 9. This value as an example is calculated when the conditions described in the "Conditions" column are met. Refer to Note 8 above to calculate the maximum transfer rate under conditions of the customer.
- Caution Select the TTL input buffer for the RxDg pin and the N-ch open drain output (VDD tolerance) mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VIH and V<sub>IL</sub>, see the DC characteristics with TTL input buffer selected.





## CSI mode serial transfer timing (slave mode) (during communication at different potential) (When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.)

**Remark** p: CSI number (p = 00, 20), m: Unit number (m = 0, 1), n: Channel number (n = 0)



# (3) When reference voltage (+) = V<sub>DD</sub> (ADREFP1 = 0, ADREFP0 = 0), reference voltage (-) = V<sub>ss</sub> (ADREFM = 0), target pin: ANI0 to ANI3, ANI16 to ANI22, internal reference voltage, and temperature sensor output voltage

Parameter	Symbol	Condition	ns	MIN.	TYP.	MAX.	Unit
Resolution	Res			8		10	bit
Overall error <sup>Note 1</sup>	AINL	10-bit resolution			1.2	±7.0	LSB
					1.2	$\pm 10.5^{Note 3}$	LSB
Conversion time	<b>t</b> CONV	10-bit resolution	$3.6~V \leq V \text{DD} \leq 5.5~V$	2.125		39	μS
		Target pin: ANI0 to ANI3,	$2.7~V \leq V \text{DD} \leq 5.5~V$	3.1875		39	μs
		ANI16 to ANI22	$1.8~V \leq V \text{DD} \leq 5.5~V$	17		39	μS
				57		95	μS
Conversion time	<b>t</b> CONV	10-bit resolution	$3.6~V \leq V \text{DD} \leq 5.5~V$	2.375		39	μS
		Target pin: internal reference voltage, and temperature sensor output voltage (HS (high-speed main) mode)	$2.7 \text{ V} \leq \text{VDD} \leq 5.5 \text{ V}$	3.5625		39	μS
			$2.4~V \leq V_{DD} \leq 5.5~V$	17		39	μS
Zero-scale error <sup>Notes 1, 2</sup>	EZS	10-bit resolution				±0.60	%FSR
						±0.85 Note 3	%FSR
Full-scale error <sup>Notes 1, 2</sup>	EFS	10-bit resolution				±0.60	%FSR
						±0.85 Note 3	%FSR
Integral linearity error <sup>Note 1</sup>	ILE	10-bit resolution				±4.0	LSB
						±6.5 Note 3	LSB
Differential linearity error Note 1	DLE	10-bit resolution				±2.0	LSB
						$\pm 2.5$ Note 3	LSB
Analog input voltage	VAIN	ANI0 to ANI3, ANI16 to ANI2	2	0		VDD	V
		Internal reference voltage (2.4 V $\leq$ VDD $\leq$ 5.5 V, HS (high		VBGR Note 4		V	
		Temperature sensor output v (2.4 V $\leq$ VDD $\leq$ 5.5 V, HS (high	roltage n-speed main) mode)		VTMPS25 <sup>Note (</sup>	1	V

$(T_{A} = -40 \text{ to } +85^{\circ}\text{C})$	$18V < V_{DD} < 55V$	$V_{SS} = 0 V$ Reference	voltage (+) = Vpp	Reference voltage (	-) = Vss)
(1A = -40 10 + 05 C,		$, v_{33} = 0 v, neielence$	$=$ voltage ( $\pm$ ) = vol,	nelelence vollage (	_j <b>–</b> v ssj

**Notes 1.** Excludes quantization error ( $\pm 1/2$  LSB).

- 2. This value is indicated as a ratio (%FSR) to the full-scale value.
- 3. When the conversion time is set to 57  $\mu s$  (min.) and 95  $\mu s$  (max.).
- 4. Refer to 28.6.2 Temperature sensor/internal reference voltage characteristics.



# (4) When reference voltage (+) = Internal reference voltage (ADREFP1 = 1, ADREFP0 = 0), reference voltage (-) = AV<sub>REFM</sub> (ADREFM = 1), target pin: ANI0, ANI2, ANI3, and ANI16 to ANI22

(TA = -40 to +85°C, 2.4 V  $\leq$  V<sub>DD</sub>  $\leq$  5.5 V, V<sub>SS</sub> = 0 V, Reference voltage (+) = V<sub>BGR</sub><sup>Note 3</sup>, Reference voltage (-) = AV<sub>REFM</sub><sup>Note 4</sup> = 0 V, HS (high-speed main) mode)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Resolution	Res			8		bit
Conversion time	<b>t</b> CONV	8-bit resolution	17		39	μs
Zero-scale error <sup>Notes 1, 2</sup>	EZS	8-bit resolution			±0.60	%FSR
Integral linearity error <sup>Note 1</sup>	ILE	8-bit resolution			±2.0	LSB
Differential linearity error Note 1	DLE	8-bit resolution			±1.0	LSB
Analog input voltage	VAIN		0		VBGR Note 3	V

**Notes 1.** Excludes quantization error ( $\pm 1/2$  LSB).

2. This value is indicated as a ratio (%FSR) to the full-scale value.

### 3. Refer to 28.6.2 Temperature sensor/internal reference voltage characteristics.

4. When reference voltage (-) = Vss, the MAX. values are as follows.

Zero-scale error: Add  $\pm 0.35\%$ FSR to the MAX. value when reference voltage (–) = AV<sub>REFM</sub>. Integral linearity error: Add  $\pm 0.5$  LSB to the MAX. value when reference voltage (–) = AV<sub>REFM</sub>. Differential linearity error: Add  $\pm 0.2$  LSB to the MAX. value when reference voltage (–) = AV<sub>REFM</sub>.



# <R> 3. ELECTRICAL SPECIFICATIONS (G: INDUSTRIAL APPLICATIONS $T_A = -40$ to +105°C)

<R> This chapter describes the following electrical specifications.

Target products G: Industrial applications  $T_A = -40$  to  $+105^{\circ}C$ 

<R> R5F102xxGxx

- **Cautions 1.** The RL78 microcontrollers have an on-chip debug function, which is provided for development and evaluation. Do not use the on-chip debug function in products designated for mass production, because the guaranteed number of rewritable times of the flash memory may be exceeded when this function is used, and product reliability therefore cannot be guaranteed. Renesas Electronics is not liable for problems occurring when the on-chip debug function is used.
  - 2. The pins mounted depend on the product. Refer to 2.1 Port Functions to 2.2.1 Functions for each product.
  - **3.** Please contact Renesas Electronics sales office for derating of operation under  $T_A = +85^{\circ}C$  to  $+105^{\circ}C$ . Derating is the systematic reduction of load for the sake of improved reliability.

# Remark When the RL78 microcontroller is used in the range of T<sub>A</sub> = -40 to +85 °C, see CHAPTER 28 <R> ELECTRICAL SPECIFICATIONS (A: T<sub>A</sub> = -40 to +85 °C).

There are following differences between the products "G: Industrial applications ( $T_A = -40$  to  $+105^{\circ}C$ )" and the products "A: Consumer applications, and D: Industrial applications".

Parameter	Application			
	A: Consumer applications, D: Industrial applications	G: Industrial applications		
Operating ambient temperature	T <sub>A</sub> = -40 to +85°C	T <sub>A</sub> = -40 to +105°C		
Operating mode	HS (high-speed main) mode:	HS (high-speed main) mode only:		
Operating voltage range	2.7 V $\leq$ V_{DD} $\leq$ 5.5 V@1 MHz to 24 MHz	$2.7~V \leq V_{\text{DD}} \leq 5.5~V@1~\text{MHz}$ to 24 MHz		
	2.4 V $\leq$ V_{DD} $\leq$ 5.5 V@1 MHz to 16 MHz	2.4 V $\leq$ V_{DD} $\leq$ 5.5 V@1 MHz to 16 MHz		
	LS (low-speed main) mode:			
	1.8 V $\leq$ V <sub>DD</sub> $\leq$ 5.5 V@1 MHz to 8 MHz			
High-speed on-chip oscillator clock	R5F102 products, 1.8 V $\leq$ V <sub>DD</sub> $\leq$ 5.5 V:	R5F102 products, 2.4 V $\leq$ V <sub>DD</sub> $\leq$ 5.5 V:		
accuracy	±1.0%@ T <sub>A</sub> = -20 to +85°C	±2.0%@ T <sub>A</sub> = +85 to +105°C		
	$\pm 1.5\%$ @ T <sub>A</sub> = -40 to -20°C	±1.0%@ T <sub>A</sub> = -20 to +85°C		
	R5F103 products, 1.8 V $\leq$ V <sub>DD</sub> $\leq$ 5.5 V:	±1.5%@ T <sub>A</sub> = -40 to -20°C		
	±5.0%@ T <sub>A</sub> = -40 to +85°C			
Serial array unit	UART	UART		
	CSI: fcLk/2 (supporting 12 Mbps), fcLk/4	CSI: fclk/4		
	Simplified I <sup>2</sup> C communication	Simplified I <sup>2</sup> C communication		
Voltage detector	Rise detection voltage: 1.88 V to 4.06 V	Rise detection voltage: 2.61 V to 4.06 V		
	(12 levels)	(8 levels)		
	Fall detection voltage: 1.84 V to 3.98 V	Fall detection voltage: 2.55 V to 3.98 V		
	(12 levels)	(8 levels)		

Remark The electrical characteristics of the products G: Industrial applications (T<sub>A</sub> = -40 to +105°C) are different from those of the products "A: Consumer applications, and D: Industrial applications". For details, refer to 29.1 to 29.10.



### (3) Peripheral functions (Common to all products)

### $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, \text{ V}_{SS} = 0 \text{ V})$

Parameter	Symbol		Conditions	MIN.	TYP.	MAX.	Unit
Low-speed onchip oscillator operating current	IFIL Note 1				0.20		μA
12-bit interval timer operating current	ITMKA Notes 1, 2, 3						μA
Watchdog timer operating current	WDT Notes 1, 2, 4	fı∟ = 15 kHz			0.22		μA
A/D converter		When conversion	Normal mode, $AV_{REFP} = V_{DD} = 5.0 V$		1.30	1.70	mA
operating current	Notes 1, 5	at maximum speed	Low voltage mode, AV <sub>REFP</sub> = V <sub>DD</sub> = 3.0 V		0.50	0.70	mA
A/D converter reference voltage operating current	IADREF Note 1				75.0		μA
Temperature sensor operating current	ITMPS Note 1				75.0		μA
LVD operating current	LVD Notes 1, 6				0.08		μA
Self-programming operating current	FSP Notes 1, 8				2.00	12.20	mA
BGO operating current	BGO Notes 1, 7				2.00	12.20	mA
SNOOZE operating	Isnoz	ADC operation	The mode is performed Note 9		0.50	1.10	mA
current	Note 1		The A/D conversion operations are performed, Low voltage mode, AV <sub>REFP</sub> = $V_{DD} = 3.0 \text{ V}$		1.20	2.04	mA
		CSI/UART operation	1		0.70	1.54	mA

Notes 1. Current flowing to the VDD.

- 2. When high speed on-chip oscillator and high-speed system clock are stopped.
- 3. Current flowing only to the 12-bit interval timer (excluding the operating current of the low-speed on-chip oscillator). The current value of the RL78 microcontrollers is the sum of IDD1, IDD2 or IDD3, and IFIL and ITMKA when the 12-bit interval timer operates.
- 4. Current flowing only to the watchdog timer (including the operating current of the low-speed on-chip oscillator). The current value of the RL78 microcontrollers is the sum of IDD1, IDD2 or IDD3 and IWDT when the watchdog timer operates.
- 5. Current flowing only to the A/D converter. The current value of the RL78 microcontrollers is the sum of IDD1 or IDD2 and IADC when the A/D converter operates in an operation mode or the HALT mode.
- 6. Current flowing only to the LVD circuit. The current value of the RL78 microcontrollers is the sum of IDD1, IDD2 or IDD3 and ILVD when the LVD circuit operates.
- 7. Current flowing only during data flash rewrite.
- **8.** Current flowing only during self programming.
- 9. For shift time to the SNOOZE mode, see 17.3.3 SNOOZE mode.

Remarks 1. fil: Low-speed on-chip oscillator clock frequency

**2.** Temperature condition of the TYP. value is  $T_A = 25^{\circ}C$ 



Parameter	Symbol	Conditions		Conditions		Conditions HS (high-speed main) Mod		Unit
				MIN.	MAX.			
SCKp cycle time	tксүı	$t_{KCY1} \geq 4/f_{CLK}$	$2.7~V \leq V_{\text{DD}} \leq 5.5~V$	334		ns		
			$2.4~V \leq V_{\text{DD}} \leq 5.5~V$	500		ns		
SCKp high-/low-level width	tкнı,	$4.0 \text{ V} \leq \text{V}_{\text{DD}} \leq 5.5 \text{ V}$		tксү1/2–24		ns		
	tĸ∟1	$2.7~V \leq V_{\text{DD}} \leq 5.5~V$		tксү1/2–36		ns		
		$2.4~V \leq V_{\text{DD}} \leq 5.5~V$		tксү1/2-76		ns		
SIp setup time (to SCKp↑) <sup>Note 1</sup>	tsik1	$4.0~V \leq V_{\text{DD}} \leq 5.5$	V	66		ns		
		$2.7~V \leq V_{\text{DD}} \leq 5.5$	V	66		ns		
		$2.4~V \leq V_{\text{DD}} \leq 5.5$	V	113		ns		
SIp hold time (from SCKp↑) Note 2	tksi1			38		ns		
Delay time from SCKp↓ to SOp output <sup>Note 3</sup>	tkso1	C = 30 pF <sup>Note4</sup>			50	ns		

(2)	During communication at same potential (CSI mode) (master mode, SCKp internal clock outpu	t)
(T/	$A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, \text{ V}_{SS} = 0 \text{ V})$	

- **Notes 1.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time becomes "to  $SCKp\downarrow$ " when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
  - 2. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp hold time becomes "from SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
  - **3.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp<sup>↑</sup>" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
  - 4. C is the load capacitance of the SCKp and SOp output lines.
- **Caution** Select the normal input buffer for the SIp pin and the normal output mode for the SOp and SCKp pins by using port input mode register 1 (PIM1) and port output mode registers 0, 1, 4 (POM0, POM1, POM4).
- **Remarks 1.** p: CSI number (p = 00, 01, 11, 20), m: Unit number (m = 0, 1), n: Channel number (n = 0, 1, 3)
  - 2. fmck: Serial array unit operation clock frequency
    - (Operation clock to be set by the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn). m: Unit number (m = 0, 1), n: Channel number (n = 0, 1, 3))





### CSI mode serial transfer timing (during communication at same potential) (When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.)





- Remarks 1. p: CSI number (p = 00, 01, 11, 20), m: Unit number (m = 0, 1), n: Channel number (n = 0, 1, 3)
  2. fMCK: Serial array unit operation clock frequency
  - (Operation clock to be set by the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn). m: Unit number (m = 0, 1), n: Channel number (n = 0, 1, 3))



(6) Communication at different potential (1.8 V, 2.5 V, 3 V) (CSI mode) (master mode, SCKp... internal clock output) (1/3)

Parameter	Symbol		Conditions	HS (high-spee	ed main) Mode	Unit
				MIN.	MAX.	
SCKp cycle time	tkcy1	$t_{\text{KCY1}} \geq 4/f_{\text{CLK}}$	$4.0~V \leq V_{\text{DD}} \leq 5.5~V,$	600		ns
			$2.7~V \leq V_b \leq 4.0~V,$			
			$C_b$ = 30 pF, $R_b$ = 1.4 k $\Omega$			
			$2.7~V \leq V_{\text{DD}} < 4.0~V,$	1000		ns
			$2.3~V \leq V_b \leq 2.7~V,$			
			$C_b=30 \text{ pF},  R_b=2.7  \text{k}\Omega$			
			$2.4~V \leq V_{\text{DD}} < 3.3~V,$	2300		ns
			$1.6~V \leq V_b \leq 2.0~V,$			
			$C_b$ = 30 pF, $R_b$ = 5.5 k $\Omega$			
SCKp high-level width	tкнı	$4.0~V \le V_{\text{DD}} \le 5$	$4.0 \ V \leq V_{\text{DD}} \leq 5.5 \ V, \ 2.7 \ V \leq V_{\text{b}} \leq 4.0 \ V,$			ns
		$C_b = 30 \text{ pF}, \text{ R}_b$	= 1.4 kΩ			
		$2.7 \text{ V} \leq \text{V}_{\text{DD}}$ < 4	4.0 V, 2.3 V $\leq$ V <sub>b</sub> $\leq$ 2.7 V,	tксү1/2 –340		ns
		$C_b = 30 \text{ pF}, \text{ R}_b$	= 2.7 kΩ			
		$2.4 \text{ V} \leq \text{V}_{\text{DD}} < 3$	3.3 V, 1.6 V $\leq$ V <sub>b</sub> $\leq$ 2.0 V,	tксү1/2-916		ns
		$C_b = 30 \text{ pF}, \text{ R}_b$	= 5.5 kΩ			
SCKp low-level width	tĸ∟1	$4.0~V \le V_{\text{DD}} \le 5$	5.5 V, 2.7 V $\leq$ V <sub>b</sub> $\leq$ 4.0 V,	tксү1/2 –24		ns
		$C_b = 30 \text{ pF}, R_b$	= 1.4 kΩ			
		$2.7 \text{ V} \leq \text{V}_{\text{DD}}$ < 4	4.0 V, 2.3 V $\leq$ V <sub>b</sub> $\leq$ 2.7 V,	tксү1/2 –36		ns
		$C_b = 30 \text{ pF}, R_b$	= 2.7 kΩ			
		$2.4 V \le V_{DD} < 3$	$3.3 \text{ V}, 1.6 \text{ V} \le \text{V}_{b} \le 2.0 \text{ V},$	tксү1/2 –100		ns
		$C_b = 30 \text{ pF}, R_b$	= 5.5 kΩ			

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{V}_{DD} \le \text{V}_{DD} \le 5.5 \text{ V}, \text{V}_{SS} = 0 \text{ V})$ 

- Cautions 1. Select the TTL input buffer for the SIp pin and the N-ch open drain output (V<sub>DD</sub> tolerance) mode for the SOp pin and SCKp pin by using port input mode register 1 (PIM1) and port output mode register 1 (POM1). For V<sub>IH</sub> and V<sub>IL</sub>, see the DC characteristics with TTL input buffer selected.
  - 2. CSI01 and CSI11 cannot communicate at different potential.
- **Remarks 1.** R<sub>b</sub> [Ω]: Communication line (SCKp, SOp) pull-up resistance, C<sub>b</sub> [F]: Communication line (SCKp, SOp) load capacitance, V<sub>b</sub> [V]: Communication line voltage
  - **2.** p: CSI number (p = 00, 20)





### CSI mode serial transfer timing (slave mode) (during communication at different potential) (When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.)

**Remark** p: CSI number (p = 00, 20), m: Unit number (m = 0, 1), n: Channel number (n = 0)



Parameter	Symbol	Conditions	HS (high-s Mo	peed main) ode	Unit
			MIN.	MAX.	
SCLr clock frequency	fsc∟	$\begin{array}{l} 4.0 \; V \leq V_{DD} \leq 5.5 \; V,  2.7 \; V \leq V_b \leq 4.0 \; V, \\ C_b = 100 \; pF, \; R_b = 2.8 \; k\Omega \end{array}$		100 <sup>Note1</sup>	kHz
		$\label{eq:VD} \begin{array}{l} 2.7 \ V \leq V_{\text{DD}} < 4.0 \ V, \ 2.3 \ V \leq V_{\text{b}} \leq 2.7 \ V, \\ C_{\text{b}} = 100 \ pF, \ R_{\text{b}} = 2.7 \ k\Omega \end{array}$		100 <sup>Note1</sup>	kHz
		$\label{eq:VD} \begin{array}{l} 2.4 \ V \leq V_{\text{DD}} < 3.3 \ V, \ 1.6 \ V \leq V_{\text{b}} \leq 2.0 \ V, \\ \\ C_{\text{b}} = 100 \ pF, \ R_{\text{b}} = 5.5 \ k\Omega \end{array}$		100 <sup>Note1</sup>	kHz
Hold time when SCLr = "L"	t∟ow	$\begin{array}{l} 4.0 \; V \leq V_{\text{DD}} \leq 5.5 \; V,  2.7 \; V \leq V_{\text{b}} \leq 4.0 \; V, \\ C_{\text{b}} = 100 \; p\text{F}, \; R_{\text{b}} = 2.8 \; \text{k}\Omega \end{array}$	4600		ns
		$\label{eq:VD} \begin{array}{l} 2.7 \ V \leq V_{\text{DD}} < 4.0 \ V, \ 2.3 \ V \leq V_{\text{b}} \leq 2.7 \ V, \\ C_{\text{b}} = 100 \ pF, \ R_{\text{b}} = 2.7 \ k\Omega \end{array}$	4600		ns
		$\label{eq:VD} \begin{array}{l} 2.4 \ V \leq V_{DD} < 3.3 \ V, \ 1.6 \ V \leq V_b \leq 2.0 \ V, \\ \\ C_b = 100 \ pF, \ R_b = 5.5 \ k\Omega \end{array}$	4650		ns
Hold time when SCLr = "H"	tніgн	$\begin{array}{l} \mbox{4.0 V} \leq V_{\text{DD}} \leq 5.5 \ \text{V}, \ 2.7 \ \text{V} \leq V_{\text{b}} \leq 4.0 \ \text{V}, \\ \mbox{C}_{\text{b}} = 100 \ \text{pF}, \ R_{\text{b}} = 2.8 \ \text{k}\Omega \end{array}$	2700		ns
		$\label{eq:VD} \begin{array}{l} 2.7 \ V \leq V_{\text{DD}} < 4.0 \ V, \ 2.3 \ V \leq V_{\text{b}} \leq 2.7 \ V, \\ C_{\text{b}} = 100 \ pF, \ R_{\text{b}} = 2.7 \ k\Omega \end{array}$	2400		ns
		$\begin{array}{l} 2.4 \ V \leq V_{DD} < 3.3 \ V, \ 1.6 \ V \leq V_b \leq 2.0 \ V, \\ C_b = 100 \ pF, \ R_b = 5.5 \ k\Omega \end{array}$	1830		ns
Data setup time (reception)	tsu:dat	$\begin{array}{l} 4.0 \; V \leq V_{\text{DD}} \leq 5.5 \; V,  2.7 \; V \leq V_{\text{b}} \leq 4.0 \; V, \\ C_{\text{b}} = 100 \; pF, \; R_{\text{b}} = 2.8 \; k\Omega \end{array}$	1/f <sub>MCK</sub> + 760 <sup>Note3</sup>		ns
		$\label{eq:VD} \begin{array}{l} 2.7 \ V \leq V_{\text{DD}} < 4.0 \ V, \ 2.3 \ V \leq V_{\text{b}} \leq 2.7 \ V, \\ C_{\text{b}} = 100 \ pF, \ R_{\text{b}} = 2.7 \ k\Omega \end{array}$	1/fмск + 760 <sup>Note3</sup>		ns
		$\label{eq:VD} \begin{array}{l} 2.4 \ V \leq V_{DD} < 3.3 \ V, \ 1.6 \ V \leq V_b \leq 2.0 \ V, \\ \\ C_b = 100 \ pF, \ R_b = 5.5 \ k\Omega \end{array}$	1/fмск + 570 <sup>Note3</sup>		ns
Data hold time (transmission)	thd:dat		0	1420	ns
		$ \begin{array}{l} 2.7 \ V \leq V_{DD} < 4.0 \ V, \ 2.3 \ V \leq V_b \leq 2.7 \ V, \\ C_b = 100 \ pF, \ R_b = 2.7 \ k\Omega \end{array} $	0	1420	ns
		$\label{eq:VD} \begin{array}{l} 2.4 \ V \leq V_{DD} < 3.3 \ V, \ 1.6 \ V \leq V_b \leq 2.0 \ V, \\ \\ C_b = 100 \ pF, \ R_b = 5.5 \ k\Omega \end{array}$	0	1215	ns

# (8) Communication at different potential (1.8 V, 2.5 V, 3 V) (simplified $l^2C$ mode)

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, \text{V}_{SS} = 0 \text{ V})$ 

**Notes 1.** The value must also be equal to or less than  $f_{MCK}/4$ .

2. Set tsu:DAT so that it will not exceed the hold time when SCLr = "L" or SCLr = "H".

- Cautions 1. Select the TTL input buffer and the N-ch open drain output (V<sub>DD</sub> tolerance) mode for the SDAr pin and the N-ch open drain output (V<sub>DD</sub> tolerance) mode for the SCLr pin by using port input mode register 1 (PIM1) and port output mode register 1 (POM1). For V<sub>IH</sub> and V<sub>IL</sub>, see the DC characteristics with TTL input buffer selected.
  - 2. IIC01 and IIC11 cannot communicate at different potential.

(Remarks are listed on the next page.)



### 3.6 Analog Characteristics

### 3.6.1 A/D converter characteristics

Classification of A/D converter characteristics

Input channel	Reference Voltage						
	Reference voltage (+) = AVREFP Reference voltage (-) = AVREFM	Reference voltage (+) = VDD Reference voltage (-) = Vss	Reference voltage (+) = VBGR Reference voltage (-) = AVREFM				
ANI0 to ANI3	Refer to 29.6.1 (1).	Refer to 29.6.1 (3).	Refer to 29.6.1 (4).				
ANI16 to ANI22	Refer to <b>29.6.1 (2)</b> .						
Internal reference voltage	Refer to 29.6.1 (1).		-				
Temperature sensor output voltage							

(1) When reference voltage (+) = AV<sub>REFP</sub>/ANI0 (ADREFP1 = 0, ADREFP0 = 1), reference voltage (-) = AV<sub>REFM</sub>/ANI1 (ADREFM = 1), target pin: ANI2, ANI3, internal reference voltage, and temperature sensor output voltage

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{AV}_{REFP} \le \text{VDD} \le 5.5 \text{ V}, \text{Vss} = 0 \text{ V}, \text{Reference voltage (+)} = \text{AV}_{REFP}, \text{Reference voltage (-)} = \text{AV}_{REFM} = 0 \text{ V})$ 

Parameter	Symbol	Cor	ditions	MIN.	TYP.	MAX.	Unit
Resolution	RES		8		10	bit	
Overall error <sup>Note 1</sup>	AINL	10-bit resolution AVREFP = VDD Note 3		1.2	±3.5	LSB	
Conversion time	<b>t</b> CONV	10-bit resolution 3.6	$3.6~V \leq V \text{DD} \leq 5.5~V$	2.125		39	μS
		Target pin: ANI2, ANI3	$2.7~V \leq V \text{DD} \leq 5.5~V$	3.1875		39	μs
			$2.4~V \leq V \text{DD} \leq 5.5~V$	17		39	μS
		10-bit resolution	$3.6~V \leq V \text{DD} \leq 5.5~V$	2.375		39	μS
		Target pin: Internal	$2.7~V \leq V \text{DD} \leq 5.5~V$	3.5625		39	μS
		reference voltage, and temperature sensor output voltage (HS (high-speed main) mode)	$2.4 \text{ V} \leq \text{VDD} \leq 5.5 \text{ V}$	17		39	μS
Zero-scale error <sup>Notes 1, 2</sup>	EZS	10-bit resolution AVREFP = VDD Note 3				±0.25	%FSR
Full-scale error <sup>Notes 1, 2</sup>	EFS	10-bit resolution AVREFP = VDD Note 3			±0.25	%FSR	
Integral linearity error <sup>Note 1</sup>	ILE	10-bit resolution AVREFP = VDD Note 3			±2.5	LSB	
Differential linearity error	DLE	10-bit resolution AV <sub>REFP</sub> = V <sub>DD</sub> <sup>Note 3</sup>			±1.5	LSB	
Analog input voltage	VAIN	ANI2, ANI3		0		AVREFP	V
		Internal reference voltage (HS (high-speed main) mode)		VBGR Note 4			V
		Temperature sensor outp (HS (high-speed main) m	ut voltage ode)	VTMPS25 Note 4			V

(Notes are listed on the next page.)



(3) When reference voltage (+) = V<sub>DD</sub> (ADREFP1 = 0, ADREFP0 = 0), reference voltage (-) = V<sub>ss</sub> (ADREFM = 0), target pin: ANI0 to ANI3, ANI16 to ANI22, internal reference voltage, and temperature sensor output voltage

Parameter	Symbol	Condition	ns	MIN.	TYP.	MAX.	Unit
Resolution	Res			8		10	bit
Overall error <sup>Note 1</sup>	AINL	10-bit resolution		1.2	±7.0	LSB	
Conversion time	<b>t</b> CONV	10-bit resolution	$3.6~V \leq V \text{DD} \leq 5.5~V$	2.125		39	μS
		Target pin: ANI0 to ANI3,	$2.7~V \leq V \text{DD} \leq 5.5~V$	3.1875		39	μS
		ANI16 to ANI22	$2.4~V \leq V \text{DD} \leq 5.5~V$	17		39	μs
Conversion time	<b>t</b> CONV	10-bit resolution	$3.6~V \leq V \text{DD} \leq 5.5~V$	2.375		39	μS
		Target pin: internal reference2.7voltage, and temperature2.4sensor output voltage (HS2.4(high-speed main) mode)1	$2.7 \text{ V} \leq \text{Vdd} \leq 5.5 \text{ V}$	3.5625		39	μs
			$2.4~V \leq V \text{DD} \leq 5.5~V$	17		39	μS
Zero-scale error <sup>Notes 1, 2</sup>	EZS	10-bit resolution				±0.60	%FSR
Full-scale error <sup>Notes 1, 2</sup>	EFS	10-bit resolution	)-bit resolution			±0.60	%FSR
Integral linearity error <sup>Note 1</sup>	ILE	10-bit resolution	0-bit resolution			±4.0	LSB
Differential linearity error Note 1	DLE	10-bit resolution	10-bit resolution			±2.0	LSB
Analog input voltage	VAIN	ANI0 to ANI3, ANI16 to ANI2	2	0		VDD	V
		Internal reference voltage		VBGR Note 3		V	
		(HS (high-speed main) mode)					
		Temperature sensor output voltage (HS (high-speed main) mode)		VTMPS25 Note 3			V

(T 40 to 105%)	$24V \leq V_{\rm PP} \leq 55V$	Vec - 0 V Deference	$voltogo(v) - V_{pp}$	Peterspec voltage () =	<b>/</b> 00)
(1A = -40 10 + 105 C	$, \mathbf{Z.4} \mathbf{V} \leq \mathbf{V} \mathbf{D} \mathbf{D} \leq 5.5 \mathbf{V},$	vss = 0 v, neierence	vonage(+) = voo,	reference voltage (-) = v	rssj

**Notes 1.** Excludes quantization error ( $\pm 1/2$  LSB).

2. This value is indicated as a ratio (%FSR) to the full-scale value.

3. Refer to 29.6.2 Temperature sensor/internal reference voltage characteristics.



<R>

### <R> 3.7 RAM Data Retention Characteristics

### $(T_A = -40 \text{ to } +105^{\circ}\text{C}, V_{SS} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Data retention supply voltage	VDDDR		1.44 <sup>Note</sup>		5.5	V

<R> Note This depends on the POR detection voltage. For a falling voltage, data in RAM are retained until the voltage reaches the level that triggers a POR reset but not once it reaches the level at which a POR reset is generated.



## 3.8 Flash Memory Programming Characteristics

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
System clock frequency	fclк		1		24	MHz
Code flash memory rewritable times Notes 1, 2, 3	Cerwr	Retained for 20 years $T_A = 85^{\circ}C^{Notes 4}$	1,000			Times
Data flash memory rewritable times Notes 1, 2, 3		Retained for 1 year $T_A = 25^{\circ}C^{Notes 4}$		1,000,000		
		Retained for 5 years TA = $85^{\circ}C^{Notes 4}$	100,000			
		Retained for 20 years TA = $85^{\circ}C^{Notes 4}$	10,000			

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{V}_{\text{DD}} \le 5.5 \text{ V}, \text{V}_{\text{SS}} = 0 \text{ V})$ 

**Notes 1.** 1 erase + 1 write after the erase is regarded as 1 rewrite. The retaining years are until next rewrite after the rewrite.

- 2. When using flash memory programmer and Renesas Electronics self programming library
- **3.** These are the characteristics of the flash memory and the results obtained from reliability testing by Renesas Electronics Corporation.
- 4. This temperature is the average value at which data are retained.

